

TOSHIBA Power MOS FET Module Silicon N Channel MOS Type (Four L<sup>2</sup>-π-MOSV in One)

## MP4410

High Power, High Speed Switching Applications  
 Hammer Drive, Pulse Motor Drive and Inductive Load Switching

- 4-V gate drivability
- Small package by full molding (SIP 12 pin)
- High drain power dissipation (4-device operation)  
 : P<sub>T</sub> = 28 W (T<sub>c</sub> = 25°C)
- Low drain-source ON resistance: R<sub>DS</sub> (ON) = 0.12 Ω (typ.)
- Low leakage current: I<sub>GSS</sub> = ±10 μA (max) (V<sub>GS</sub> = ±16 V)  
 I<sub>DSS</sub> = 100 μA (max) (V<sub>DS</sub> = 60 V)
- Enhancement-mode: V<sub>th</sub> = 0.8 to 2.0 V (I<sub>D</sub> = 1 mA)

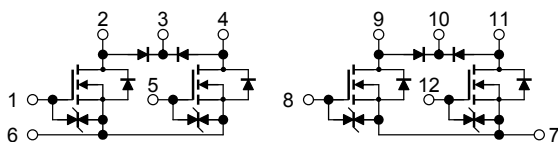
### Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Drain-source voltage	V <sub>DSS</sub>	60	V
Gate-source voltage	V <sub>GSS</sub>	±20	V
Drain current	I <sub>D</sub>	5	A
Peak drain current	I <sub>DP</sub>	20	A
Drain power dissipation (1-device operation)	P <sub>D</sub>	2.2	W
Drain power dissipation (4-device operation)	P <sub>T</sub>	T <sub>a</sub> = 25°C	4.4
		T <sub>c</sub> = 25°C	28
Channel temperature	T <sub>ch</sub>	150	°C
Storage temperature range	T <sub>stg</sub>	-55 to 150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

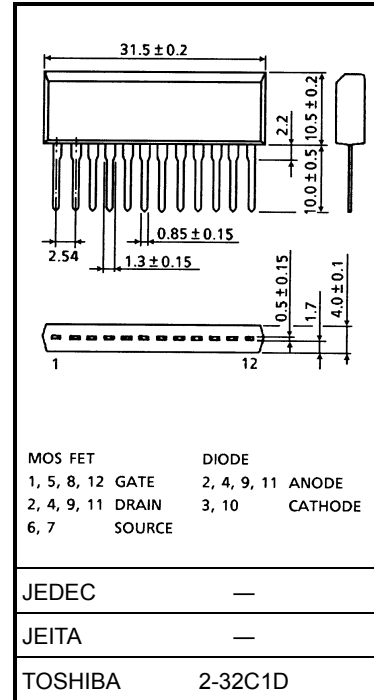
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### Array Configuration



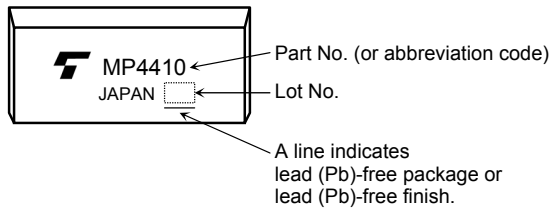
Industrial Applications

Unit: mm



Weight: 3.9 g (typ.)

## Marking



## Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance of channel to ambient (4-device operation, $T_a = 25^\circ\text{C}$ )	$\Sigma R_{\text{th (ch-a)}}$	28.4	$^\circ\text{C/W}$
Thermal resistance of channel to case (4-device operation, $T_c = 25^\circ\text{C}$ )	$\Sigma R_{\text{th (ch-c)}}$	4.46	$^\circ\text{C/W}$
Maximum lead temperature for soldering purposes (3.2 mm from case for 10 s)	$T_L$	260	$^\circ\text{C}$

This transistor is an electrostatic-sensitive device. Please handle with caution.

## Electrical Characteristics ( $T_a = 25^\circ\text{C}$ )

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		$I_{\text{GSS}}$	$V_{\text{GS}} = \pm 16 \text{ V}, V_{\text{DS}} = 0 \text{ V}$	—	—	$\pm 10$	$\mu\text{A}$
Drain cut-off current		$I_{\text{DSS}}$	$V_{\text{DS}} = 60 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	—	—	100	$\mu\text{A}$
Drain-source breakdown voltage		$V_{(\text{BR})\text{DSS}}$	$I_{\text{D}} = 10 \text{ mA}, V_{\text{GS}} = 0 \text{ V}$	60	—	—	V
Gate threshold voltage		$V_{\text{th}}$	$V_{\text{DS}} = 10 \text{ V}, I_{\text{D}} = 1 \text{ mA}$	0.8	—	2.0	V
Forward transfer admittance		$ Y_{\text{fs}} $	$V_{\text{DS}} = 10 \text{ V}, I_{\text{D}} = 2.5 \text{ A}$	3.0	5.0	—	S
Drain-source ON resistance		$R_{\text{DS (ON)}}$	$I_{\text{D}} = 2.5 \text{ A}, V_{\text{GS}} = 4 \text{ V}$	—	0.21	0.31	$\Omega$
			$I_{\text{D}} = 2.5 \text{ A}, V_{\text{GS}} = 10 \text{ V}$	—	0.12	0.16	
Input capacitance		$C_{\text{iss}}$	$V_{\text{DS}} = 10 \text{ V}, V_{\text{GS}} = 0 \text{ V}, f = 1 \text{ MHz}$	—	370	—	pF
Reverse transfer capacitance		$C_{\text{rss}}$		—	60	—	pF
Output capacitance		$C_{\text{oss}}$		—	180	—	pF
Switching time	Rise time	$t_r$		—	18	—	ns
	Turn-on time	$t_{\text{on}}$		—	25	—	
	Fall time	$t_f$		—	15	—	
	Turn-off time	$t_{\text{off}}$		—	170	—	
Total gate charge (gate-source plus gate-drain)		$Q_g$	$I_{\text{D}} = 5 \text{ A}, V_{\text{GS}} = 10 \text{ V}, V_{\text{DD}} = 48 \text{ V}$	—	12	—	nC
Gate-source charge		$Q_{\text{gs}}$		—	8	—	nC
Gate-drain ("miller") charge		$Q_{\text{gd}}$		—	4	—	nC

## Source-Drain Diode Rating and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Drain reverse current	$I_{DR}$	—	—	—	5	A
Peak drain reverse current	$I_{DRP}$	—	—	—	20	A
Diode forward voltage	$V_{DSF}$	$I_{DR} = 5 \text{ A}, V_{GS} = 0 \text{ V}$	—	—	-1.7	V

## Flyback-Diode Rating and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Maximum forward current	$I_{FM}$	—	—	—	5	A
Reverse current	$I_R$	$V_R = 120 \text{ V}$	—	—	0.4	$\mu\text{A}$
Reverse voltage	$V_R$	$I_R = 100 \mu\text{A}$	120	—	—	V
Forward voltage	$V_F$	$I_F = 1 \text{ A}$	—	—	1.8	V

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